

<b>Notice of References Cited</b>	Application/Control No. 09/604,246	Applicant(s)/Patent Under Reexamination EBIHARA ET AL.	
	Examiner Naeem Haq	Art Unit 3625	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0111914 A1	08-2002	Terada et al.	705/60
	B	US-2002/0038261 A1	03-2002	Kargman et al.	705/26
	C	US-2002/0027981 A1	03-2002	BEDROSIAN et al.	379/201.08
	D	US-2002/0016726 A1	02-2002	Ross, Kenneth J.	705/7
	E	US-6,108,639	08-2000	Walker et al.	705/26
	F	US-5,237,323	08-1993	Saito et al.	340/995.18
	G	US-5,197,009	03-1993	Hoffman et al.	701/200
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2002333832A	11-2002	Japan	APASU et al.	G09B 029/00
	O	JP362073375A	04-1987	Japan	YOKOTA, HIROSHI	G06F 015/21
	P	JP410069580A	03-1998	Japan	TSUNO, HAJIME	G07G 001/12
	Q	JP408068657A	03-1996	Japan	SUZUKI et al.	G01C 021/00
	R	JP02002251397A	09-2002	Japan	TAKEMOTO, ISAO	Go6F 017/30
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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